

Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

IKEDA, HIROYUKI

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
257	59, 64	3/6/2005	TT
257	66, 70	3/6/2005	TT
257	72, 75	3/6/2005	TT
257	365, 366	3/6/2005	TT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner